

May 1999 DISTRIBUTION GROUP\*

# MTP2955V

## P-Channel Enhancement Mode Field Effect Transistor

### **General Description**

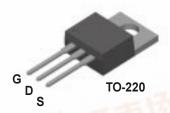
This P-Channel MOSFET has been designed specifically for low voltage, high speed switching applications i.e. power supplies and power motor controls.

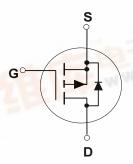
These MOSFETs feature faster switching and lower gate charge than other MOSFETs with comparable  $\rm R_{\rm DS(ON)}$  specifications.

The result is a MOSFET that is easy and safer to drive (even at very high frequencies).

### **Features**

- -12 A, -60 V.  $R_{DS(ON)} = 0.230 \Omega @ V_{GS} = -10 V$
- Critical DC electrical parameters specified at elevated temperature.
- Rugged internal source-drain diode can eliminate the need for an external Zener diode transient suppressor.
- 175°C maximum junction temperature rating.





Absolute Maximum Ratings T<sub>C</sub> = 25°C unless otherwise noted

Symbol	Parameter	Ratings	Units
V <sub>DSS</sub>	Drain-Source Voltage	-60	V
V <sub>GSS</sub>	Gate-Source Voltage	<u>+</u> 20	V
I <sub>D</sub>	Drain Current - Continuous	-12	Α
	- Pulsed	-42	
P <sub>D</sub>	Total Power Dissipation @ T <sub>C</sub> = 25∘C	60	W
	Derate above 25∘C	0.40	W/∘C
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Junction Temperature Range	-65 to +175	∘C
Therma	I Characteristics		
R <sub>0</sub> JC	Thermal Resistance, Junction-to- Case	2.5	∘C/W
R <sub>ÐJA</sub>	Thermal Resistance, Junction-to- Ambient (Note 1)	62.5	∘C/W

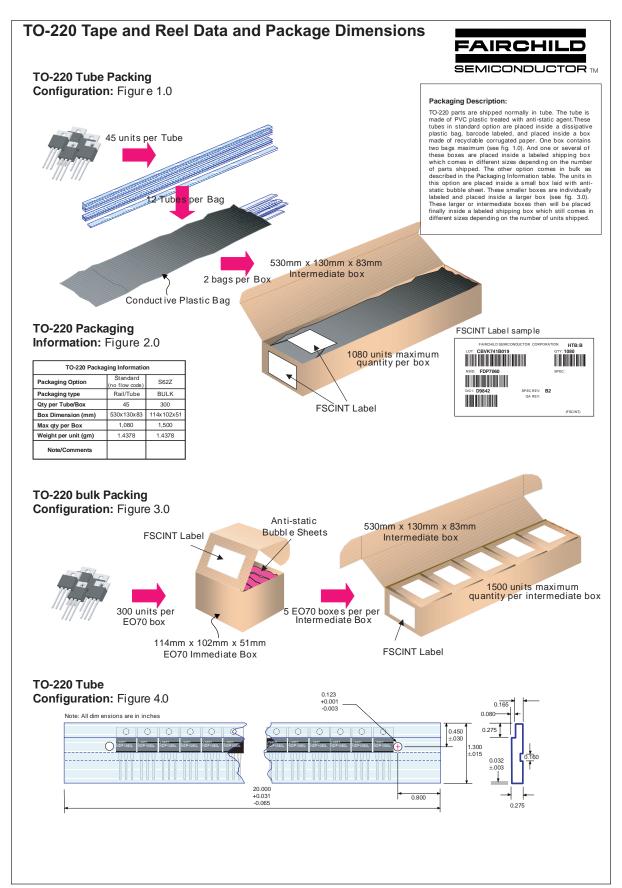
**Package Outlines and Ordering Information** 

Device Marking	Device	Device Package Information	
MTP2955V	MTP2955V	Rails/Tubes	45 units

Die and manufacturing source subject to change without prior notification.

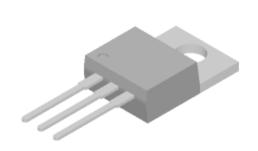
Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
DRAIN-S	OURCE AVALANCHE RAT	NGS (Note 2)				
W <sub>DSS</sub>	Single Pulse Drain-Source Avalanche Energy	$V_{DD} = -25 \text{ V}, I_{D} = -12 \text{ A}$			216	mЈ
AR	Maximum Drain-Source Avalanche	Current			-12	Α
Off Char	a atamiatia a				·	
BV <sub>DSS</sub>	acteristics Drain-Source Breakdown Voltage	$V_{GS} = 0 \ V_{r} \mid_{D} = -250 \ \mu A$	-60			V
ΔBVDSS ΛTJ	Breakdown Voltage Temperature Coefficient	I <sub>D</sub> = -250 μA, Referenced to 25°C		-63		mV/∘C
DSS	Zero Gate Voltage Drain Current	V <sub>DS</sub> = -60 V, V <sub>GS</sub> = 0 V			-10	μА
DSS	Zero Gate Voltage Drain Current	V <sub>DS</sub> = -60 V, V <sub>GS</sub> = 0 V, T <sub>J</sub> = 150°C			-100	μA
GSSF	Gate-Body Leakage Current, Forward	V <sub>GS</sub> = 20 V, V <sub>DS</sub> = 0 V			100	nA
GSSR	Gate-Body Leakage Current, Reverse	V <sub>GS</sub> = -20 V, V <sub>DS</sub> = 0 V			-100	nA
On Chara	acteristics (Note 2)					
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, \mid_{D} = -250 \mu A$	-2	-3	-4	V
∆VGS(th)	Gate Threshold Voltage Temperature Coefficient	I <sub>D</sub> = -250 μA, Referenced to 25°C		5		mV/∘C
R <sub>DS(on)</sub>	Static Drain-Source On-Resistance	V <sub>GS</sub> = -10 V,I <sub>D</sub> = -6 A,			0.230	Ω
V <sub>DS(on)</sub>	Drain Source On-Voltage	I <sub>D</sub> = -12 A, V <sub>GS</sub> = -10 V			-2.9	V
<b>g</b> <sub>FS</sub>	Forward Transconductance	$V_{DS} = -10 \text{ V}, I_{D} = -6 \text{ A}$	3.0			S
Dynamic	Characteristics					
C <sub>iss</sub>	Input Capacitance	V <sub>DS</sub> = -25 V, V <sub>GS</sub> = 0 V,			700	pF
Coss	Output Capacitance	f = 1.0 MHz			280	pF
C <sub>rss</sub>	Reverse Transfer Capacitance				100	pF
	g Characteristics (Note 2)	V <sub>DD</sub> = -30 V, I <sub>D</sub> = -12 A,		1	30	no.
t <sub>d(on)</sub>	Turn-On Delay Time	$V_{\text{GS}} = -10 \text{ V}, R_{\text{GEN}} = 9.1 \Omega$				ns
<u>t</u> ,	Turn-On Rise Time	Y SEIN STAN			100	ns
t <sub>d(off)</sub>	Turn-Off Delay Time				50	ns
t <sub>f</sub>	Turn-Off Fall Time	\ \ - 40.\\			80	ns
Q <sub>g</sub>	Total Gate Charge	$V_{DS} = -48 \text{ V},$ $I_{D} = -12 \text{ A}, V_{GS} = -10 \text{ V}$		_	30	nC
Q <sub>gs</sub>	Gate-Source Charge	1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1		3		nC
Q <sub>gd</sub>	Gate-Drain Charge			5		nC
<u>Drain-So</u>	urce Diode Characteristics		1	1		T .
S	Maximum Continuous Drain-Source				-12	Α .
SM	Maximum Pulsed Drain-Source Di	, , ,			-42	A
$V_{SD}$	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \ V_1  _{S} = -12 \ A$ (Note 2)			-3.0	V

<sup>1.</sup>  $R_{BJA}$  is the sum of the juntion-to-case and case-to-ambient thermal resistance. 2. Pulse Test: Pulse Width  $\leq$  300  $\mu$ s, Duty Cycle  $\leq$  2.0%

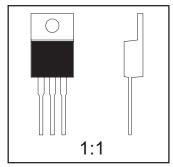


# TO-220 Tape and Reel Data and Package Dimensions, continued

# TO-220 (FS PKG Code 37)

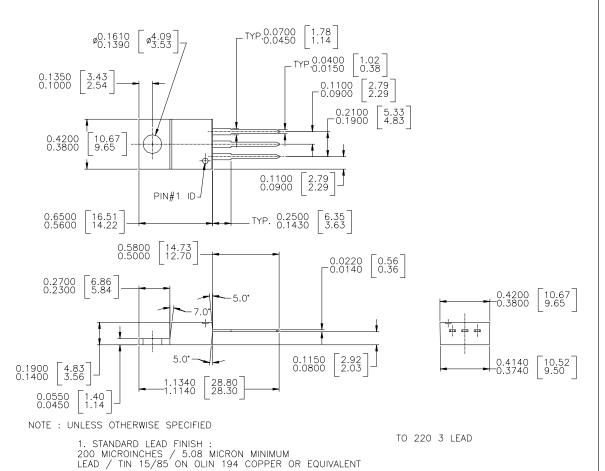


2. DIMENSION BASED ON JEDEC STANDARD TO-220 VARIATION AB, ISSUE J, DATED 3/24/87



Scale 1:1 on letter size paper
Dimensions shown below are in:
inches [millimeters]

Part Weight per unit (gram): 1.4378



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